

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination IWASAKI ET AL.	
		Examiner Vivian Chen	Art Unit 1773	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,481,184	11-2002	Junker et al.	53/413
	B	US-5,433,060	07-1995	Gur et al.	53/413
	C	US-6,221,448	04-2001	Baetzold et al.	428/35.2
	D	US-2004/0197577	10-2004	Iwasaki et al.	428/457
	E	US-2004/0197514	10-2004	Iwasaki et al.	428/040.1
	F	US-2004/0043175	03-2004	Iwasaki et al.	428/040.1
	G	US-4,013,188	03-1977	Ray, George C.	215/347
	H	US-4,629,639	12-1986	Lucas, Bennie M.	428/35.5
	I	US-5,919,863	07-1999	Seppanen et al.	525/85
	J	US-5,120,781	06-1992	Johnson, Jr., Robert W.	524/274
	K	US-2003/0113519	06-2003	Wasserman et al.	428/195
	L	US-5,366,777	11-1994	Bown et al.	428/43
	M	US-2004/0040919	03-2004	Iwasaki et al.	211/071.01

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O	EP 0 742 772	06-1999	EP	Gur et al	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.